

MS43-P15 Comparative analysis of *ex-situ* and *in-operando* X-ray diffraction experiments for lithium insertion materials

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A comparative study of *ex-situ* and *in-operando* X-ray diffraction experiments using the fast lithium ion conductor $\text{Li}_{0.18}\text{Sr}_{0.66}\text{Ti}_{1.05}\text{Nb}_{0.5}\text{O}_3$ will be presented. *Ex-situ* analysis of synchrotron X-ray diffraction data suggests that a single phase material exists for all discharges to as low as 0.422 V. For samples with higher lithium content, it is possible to determine the lithium position from the X-ray data. However, *in-operando* X-ray diffraction reveals a kinetically driven two phase region on cycling below 1 V. Monitoring the change in unit cell dimension during electrochemical cycling showed a reduction in the rate of unit cell expansion part way through the first discharge and during the second discharge, caused by a drop in lithium diffusion into the bulk material for higher lithium contents. A more significant change is a jump in the unit cell expansion once the lithium content exceeds one lithium ion per vacant site, caused by damping of octahedral rotations. This provides a link between lithium content and octahedral rotations. Using *in-operando* diffraction may therefore enable to determine the strength of octahedral rotations in defect perovskites and allow correlations with the large variance of ionic conductivities in these materials.

References

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Keywords: lithium insertion, X-ray diffraction, in-operando

MS43-P16 PHOENIX: a tender energy beamline for in-situ X-ray studies

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The PHOENIX beamline at the Swiss Light Source is specially designed for in-situ experiments covering an energy range of 400 to 8000 eV. This energy range provides opportunity to study light elements (e.g. O, Na, Mg, Al, S, Cl ... Fe) using X-ray absorption spectroscopy (XAS). The high photon flux delivered by an elliptical undulator can be focused to 2.5 μm^2 using X-ray mirrors. Topics addressed by users include environmental [1] and energy research [2], biology [3] and catalysis [4-5], as well as art preservation [6]. Experiments can be performed in two flexible vacuum end-stations, providing ample opportunity for in situ studies.

For the in-house research we focus on in situ studies of aqueous carbonate nucleation using a variety of liquid cells with precise control of the pH value, temperature and saturation index. For fast XAS measurements (ms and above) we use liquid jets [7] and for slow measurements (min to hrs) we have developed in-situ titration cells as well as flow-through cells which allow simultaneous XAS and XRD measurements. The first results obtained on CaCO_3 and $\text{Ca}(\text{Mg})\text{CO}_3$ nucleation and growth in aqueous environments will be presented. The measured XAS spectral features contain information on the local order around Mg/Ca atoms, while the XRD spectra unveils the phase transformation in time of the pure and Mg doped Ca carbonates.

For further information about the beamline: <https://www.psi.ch/sls/phoenix/phoenix>

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